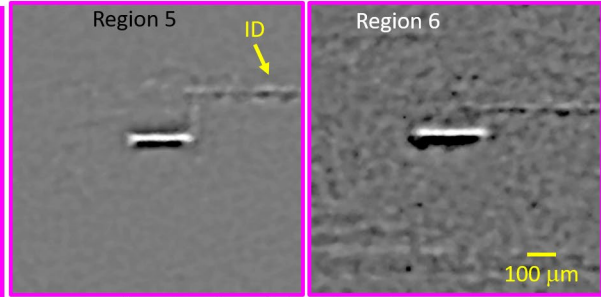
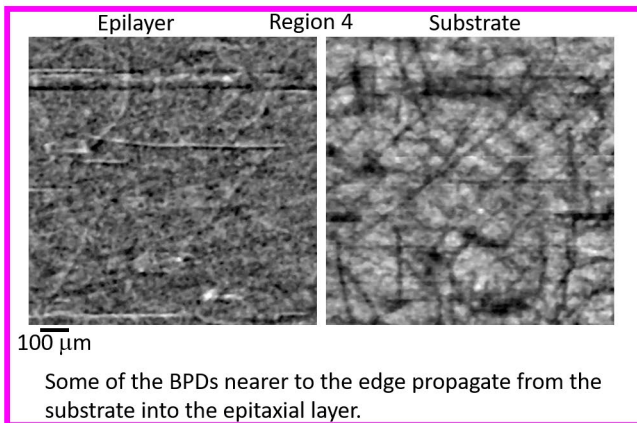
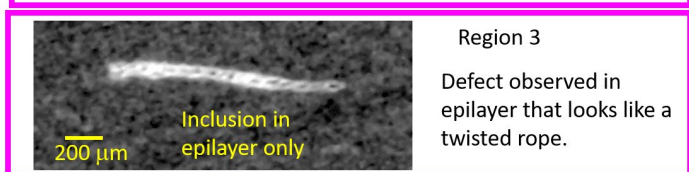
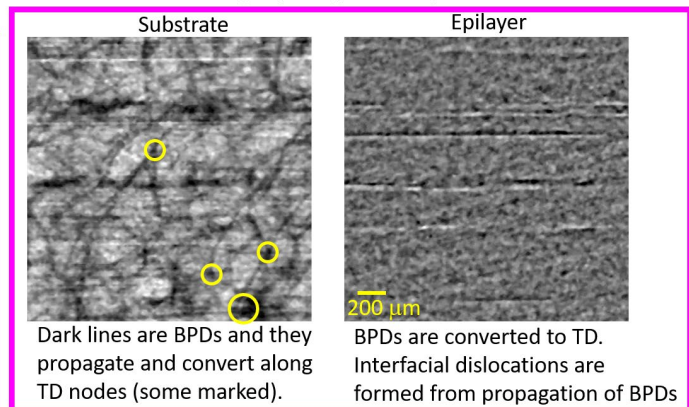
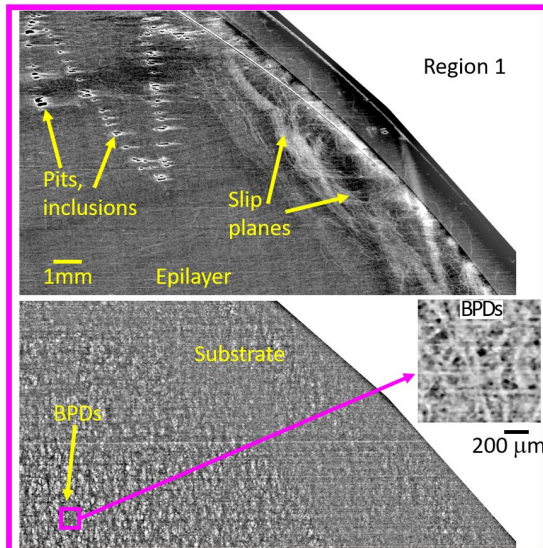
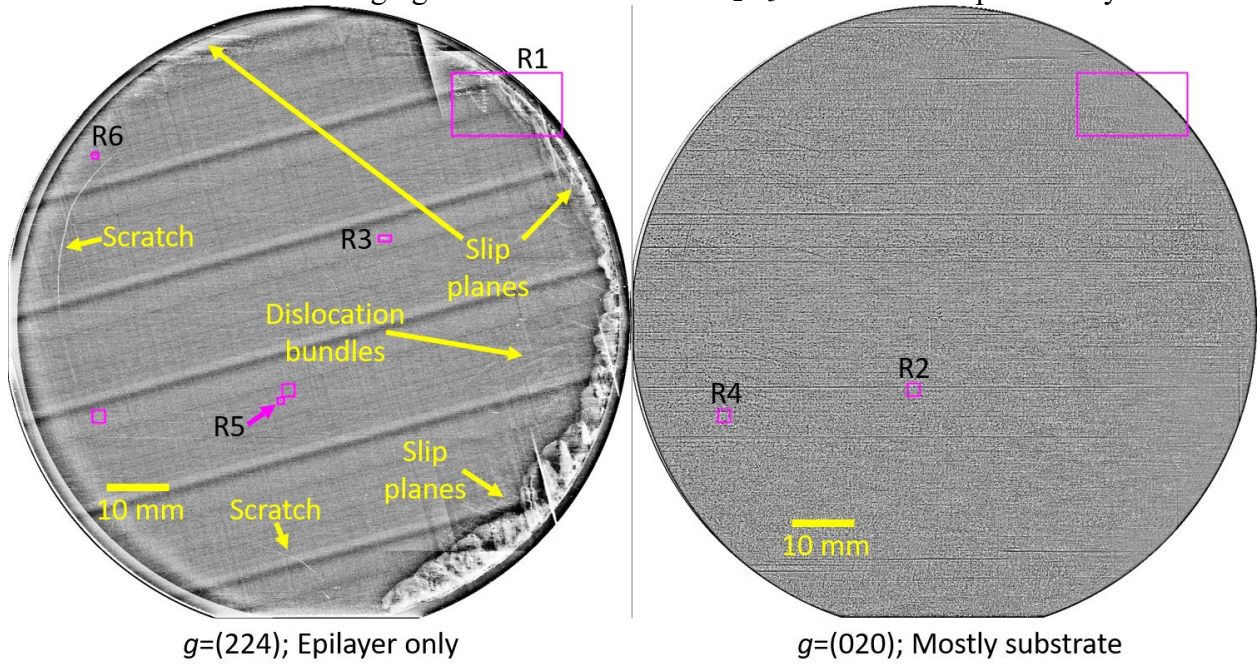


Full wafer XRT Imaging of 100mm diameter Ga_2O_3 substrate and epitaxial layers



Examples of surface dislocations that appear to be connected to interfacial dislocations (ID). The origin of these are likely from the substrate but need to be investigated.